## **Supporting Information**

## In-plane Mosaic Potential Growth of Large–Area 2D Layered Semiconductors MoS<sub>2</sub>-MoSe<sub>2</sub> Lateral Heterostructures and Photodetector Application

Xiaoshuang Chen,<sup>†, ‡</sup> Yunfeng Qiu,<sup>†</sup> Huihui Yang,<sup>†</sup> Guangbo Liu,<sup>†</sup> Wei Zheng,<sup>†</sup> Wei Feng,<sup>†</sup> Wenwu Cao,<sup>‡</sup> Wenping Hu,<sup>\*,‡,§</sup> and PingAn Hu<sup>\*,†</sup>

<sup>†</sup>Key Lab of Microsystem and Microstructure of Ministry of Education, Harbin Institute of Technology, Harbin 150080, China

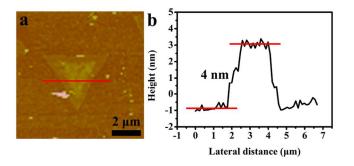
<sup>‡</sup>Department of Physics, Harbin Institute of Technology, Harbin 150080, China

<sup>§</sup>Key Laboratory of Organic Solids, Institute of Chemistry, Chinese Academy of Sciences, Beijing 100190, China

## **Corresponding Authors**

\*E-mail: hupa@hit.edu.cn. Tel: +86 451 86403583. Fax: +86 451 86403583 (P. A. Hu).

\*E-mail: huwp@iccas.ac.cn (W. P. Hu).



**Figure S1.** (a) AFM image and (b) the corresponding height profile of the mosaic  $MoS_2/MoSe_2$  lateral heterojunctions film with the thick  $MoS_2$  at the centre.

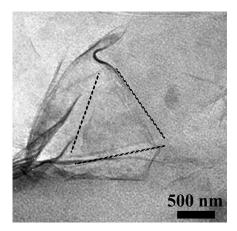


Figure S2. TEM image of mosaic  $MoS_2/MoSe_2$  lateral heterojunctions film.

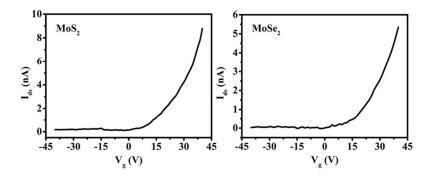
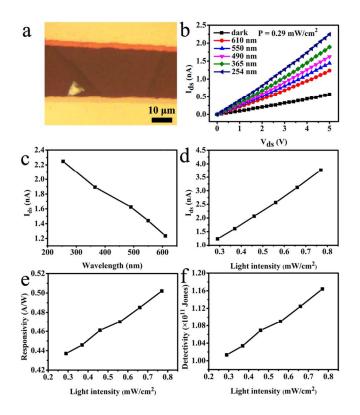
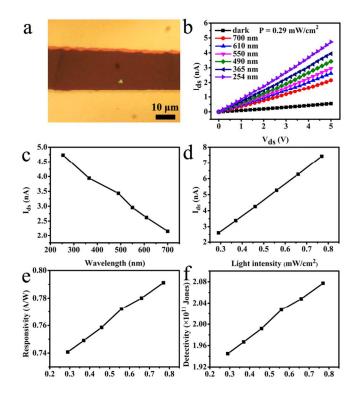


Figure S3. Transfer characteristics of the synthetic  $MoS_2$  and  $MoSe_2$  at  $V_{ds} = 1$  V.



**Figure S4.** Triangular MoS<sub>2</sub> monolayer photodetector. (a) Optical image of the photodetector device. (b)  $I_{ds}$ - $V_{ds}$  characteristic of the photodetector in dark and under various light wavelength with light intensity of 0.29 mW/cm<sup>2</sup>. (c) Photocurrent as a function of light wavelength at  $V_{ds} = 5$  V with light intensity of 0.29 mW/cm<sup>2</sup>. (d) Photocurrent as a function of light intensity with light wavelength of 610 nm at  $V_{ds} = 5$  V. Responsitivity (e) and detectivity (f) of the photodetector with different light intensity, light wavelength of 610 nm at  $V_{ds} = 5$  V.



**Figure S5.** Multilayer MoSe<sub>2</sub> film photodetector. (a) Optical image of the photodetector device. (b)  $I_{ds}$ - $V_{ds}$  characteristic of the photodetector in dark and under various light wavelength with light intensity of 0.29 mW/cm<sup>2</sup>. (c) Photocurrent as a function of light wavelength at  $V_{ds} = 5$  V with light intensity of 0.29 mW/cm<sup>2</sup>. (d) Photocurrent as a function of light intensity with light wavelength of 610 nm at  $V_{ds} = 5$  V. Responsitivity (e) and detectivity (f) of the photodetector with different light intensity, light wavelength of 610 nm at  $V_{ds} = 5$  V.

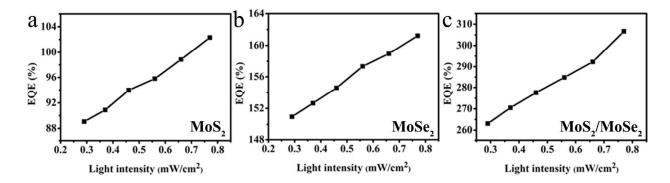


Figure S6. EQE of triangular  $MoS_2$  monolayer (a), multilayer  $MoSe_2$  film (b) and mosaic  $MoS_2/MoSe_2$  lateral heterojunctions film (c) photodetector with different light intensity, light wavelength of 610 nm at  $V_{ds} = 5$  V.